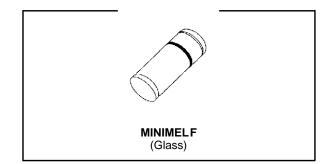


SMALL SIGNAL SCHOTTKY DIODE



DESCRIPTION

Metal to silicon junction diode featuring high breakdown, low turn-on voltage and ultrafast switching. Primarly intended for high level UHF/VHF detection and pulse application with broad dynamic range.

ABSOLUTE MAXIMUM RATINGS (limiting values)

Symbol	Parameter	Value	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	60	V
l _F	Forward Continuous Current	15	mA
I _{FSM}	Surge non Repetitive Forward Current	50	mA
T _{stg} T _j	Storage and Junction Temperature Range	- 65 to 200 -65 to 200	°C
TL	Maximum Temperature for Soldering during	260	°C

THERMAL RESISTANCE

Symbol	Test Conditions	Value	Unit
R _{th(j-l)}	Junction-leads	400	°C/W

ELECTRICAL CHARACTERISTICS

STATIC CHARACTERISTICS

l	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
	V_{BR}	$T_{amb} = 25$ °C $I_R = 10\mu A$	60			V
I	V_F^*	$T_{amb} = 25$ °C $I_F = 1$ mA			0.41	V
l		$T_{amb} = 25$ °C $I_F = 15$ mA			1	
	I _R *	$T_{amb} = 25$ °C $V_R = 50V$			0.2	μА

DYNAMIC CHARACTERISTICS

Symbol	Test Conditions			Min.	Тур.	Max.	Unit
С	T _{amb} = 25°C	$V_R = 0V$	f = 1MHz			2.2	pF
τ	T _{amb} = 25°C	$I_F = 5mA$	Krakauer Method			100	ps

^{*} Pulse test: $t_p \le 300 \mu s \ \delta < 2\%$.

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Matched batches available on request. Test conditions (forward voltage and/or capacitance) according to customer specification.

Figure 1. Forward current versus forward voltage (typical values).

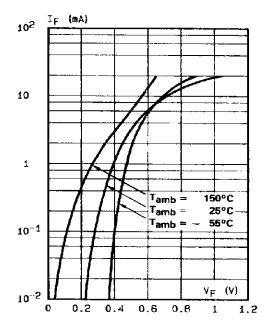


Figure 2. Capacitance C versus reverse applied voltage $V_{\mbox{\scriptsize R}}$ (typical values).

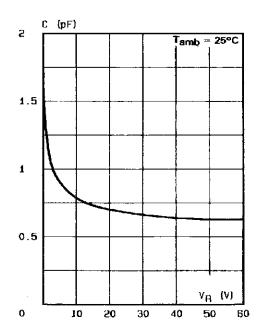


Figure 3. Reverse current versus ambient temperature.

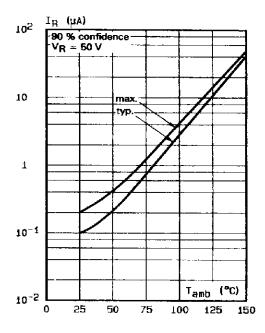
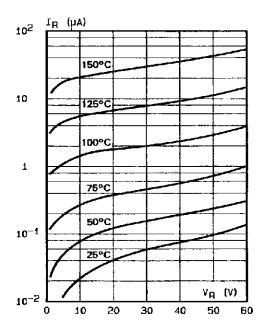


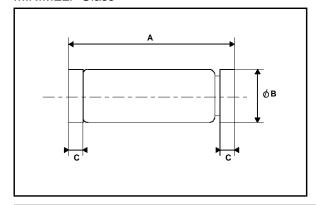
Figure 4. Reverse current versus continuous reverse voltage (typical values).

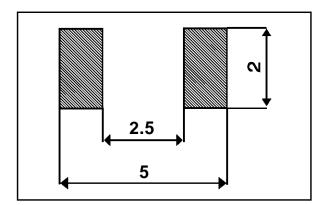


PACKAGE MECHANICAL DATA

FOOT PRINT DIMENSIONS (Millimeter)

MINIMELF Glass





	DIMENSIONS					
REF.	Millimeters		Inches			
	Min.	Max.	Min.	Max.		
Α	3.3	3.6	0.130	0.142		
В	1.59	1.62	0.063	0.064		
С	0.4	0.5	0.016	0.020		

Marking: ring at cathode end. Weight: 0.05g

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